Substitute Form PTO-1449 (Modified)			Application No. 10/814,836	•		
	Information Disclosure Statement by Applicant (Use several sheets if necessary)	Applicant Wu et al.				
(Use several s	heets if necessary)	Filing Date March 31, 2004	Group Art Unit			

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Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
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1	closure Statement oplicant	Applicant Wu et al.	•
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